TOSHIBA Photocoupler GaA As Ired + Photo IC

TLP751

Digital Logic Ground Isolation Line Receiver Microprocessor System Interfaces

Absolute Maximum Ratings (Ta = 25°C)

	Characteristic		Symbol	Rating	Unit
LED	Forward current	(Note 1)	l _F	25	mA
	Pulse forward current	(Note 2)	I _{FP}	50	mA
	Peak transient forward current	(Note 3)	I _{FPT}	1	А
	Reverse voltage		V _R	5	V
	Diode power dissipation	(Note 4)	P _D	45	mW
Detector	Output current		IO	8	mA
	Peak output current		l _{OP}	16	mA
	Output voltage		Vo	-0.5~15	V
	Supply voltage		V _{CC}	-0.5~15	V
	Base current		Ι _Β	5	mA
	Output power dissipation	(Note 5)	Po	100	mW
	Emitter-base reverse voltage		V _{EB}	5	V
Operating temperature range		T _{opr}	-55~100	°C	
Storage temperature range			T _{stg}	-55~125	°C
Lead solder temperature(10s)		(Note 6)	T _{sol}	260	°C
Isolation voltage (AC,1min.,R.H. 60%)		(Note 7)	BVS	5000	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- (Note 1) Derate 0.8mA above 70°C
- (Note 2) 50% duty cycle,1ms pulse width.

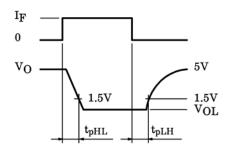
 Derate 1.6mA / °C above 70°C
- (Note 3) Pulse width 1µs,300pps.
- (Note 4) Derate 0.9mW / °C above 70°C
- (Note 5) Derate 2mW / °C above 70°C
- (Note 6) Soldering portion of lead: up to 2mm from the body of the device.
- (Note 7) Device considered a two terminal device: Pins 1,2,3 and 4 shorted together and pins 5,6,7 and 8 shorted together.

TLP751

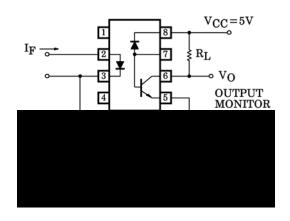
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Test Circuit 1: Switching Time Test Circuit



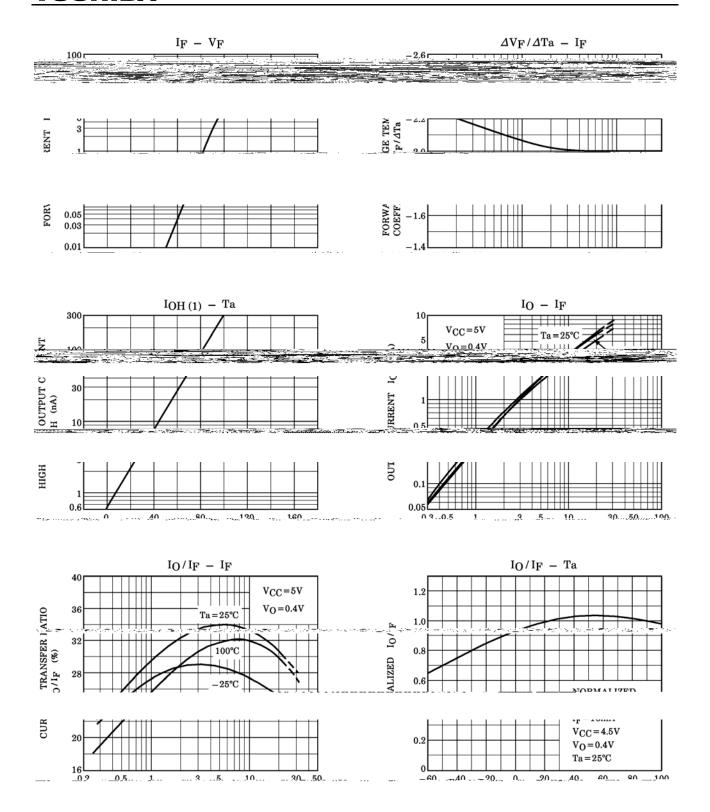


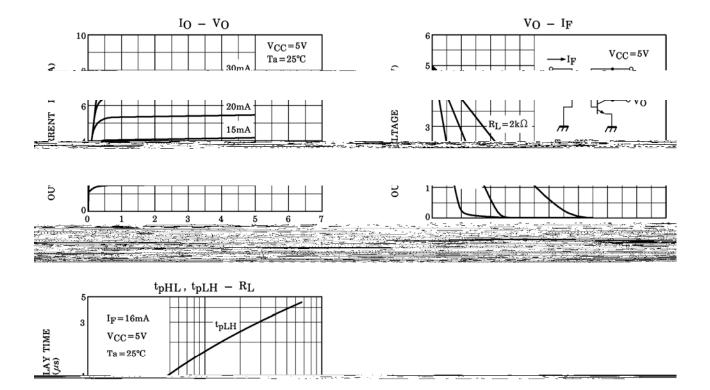
Test Circuit 2 : Common Mode Noise Immunity Test Circuit





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